

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. 238397US-2 DIV	APPLN. SERIAL NO. NEW APPLICATION 10/657,12
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT	NATSUKO NOBUKUNI, ET AL.	
		FILED	HEREWITH	GROUP 26.55

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
CG	AA	5,732,062	03/24/98	Yokoi, et al.			
CG	AB	5,848,043	12/08/98	Takada, et al.			
CG	AC	5,530,688	06/1996	Hurst, Jr., et al.			
CG	AD	6,294,310	09/2001	Ohno, et al.			
CG	AE	5,703,855	12/1997	Kirino et al.			
CG	AF	5,568,461	10/1996	Nishiuchi, et al.			
CG	AG	6,256,277 B1	07/03/01	Saga et al.			
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
CG	AO	62-259229	11/11/87	Japan		x
CG	AP	63-266632	11/02/88	Japan		x
CG	AQ	63-22439	01/29/88	Japan		x
CG	AR	7-37252	02/07/95	Japan		x
CG	AS	9-7176	01/10/97	Japan		x
CG	AT	8-287465	11/01/96	Japan		x
CG	AU	9-282661	10/31/97	Japan		x
CG	AV	7-37251	02/07/95	Japan		x

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

CG	AW	N. Nobukuni, et al. J. Appl Physics, "Microstructural changes in GeSbTe film during repetitious overwriting in phase-change optical recording," December 15, 1995, pages 6980-6988.
	AX	
	AY	
	AZ	

Examiner Muhammad Edun Primary Examiner 10/17/04 Date Considered 10/17/04

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified) LIST OF REFERENCES CITED BY APPLICANT		ATTY DOCKET NO. 238397US-2 DIV		APPLN. SERIAL NO. <u>NEW APPLICATION</u> <i>10/657,127</i>		
		APPLICANT NATSUKO NOBUKUNI, ET AL.		FILED HEREWITH		GROUP <i>2655</i>
		U.S. PATENT DOCUMENTS				
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS SUB CLASS	
	AA					
	AB					
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					
	AL					
	AM					
	AN					
FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO	
<i>RTG</i>	AO	0 887 868	09/30/98	Europe (English)		
<i>RTG</i>	AP	0 902 424	03/17/99	Europe (English)		
<i>RTG</i>	AQ	0 388 897	09/26/90	Europe (English)		
	AR					
	AS					
	AT					
	AU					
	AV					
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)						
	AW					
	AX					
	AY					
	AZ					
Examiner	Muhammad Edun Primary Examiner		<i>RE</i>	Date Considered	<i>10/17/04</i>	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						



SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 238397US2DIV	SHEET 1 OF 1		SERIAL NO. 10/657,121
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Natsuko NOBUKUNI, et al.					
		FILING DATE September 9, 2003			GROUP 2655		
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>RL</i>	AA	6,256,286	07/03/2001	M. OGAWA			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
<i>RL</i>	AO	0 847 049	06/10/1998	EUROPE	<input checked="" type="checkbox"/>	<input type="checkbox"/>	YES NO
<i>RL</i>	AP	0 217 293	04/08/1987	EUROPE	<input checked="" type="checkbox"/>	<input type="checkbox"/>	
<i>RL</i>	AQ	0 834 874	04/08/1998	EUROPE	<input checked="" type="checkbox"/>	<input type="checkbox"/>	
<i>RL</i>	AR	1 047 056	10/25/2000	EUROPE	<input checked="" type="checkbox"/>	<input type="checkbox"/>	
	AS				<input type="checkbox"/>	<input type="checkbox"/>	
	AT				<input type="checkbox"/>	<input type="checkbox"/>	
	AU				<input type="checkbox"/>	<input type="checkbox"/>	
	AV				<input type="checkbox"/>	<input type="checkbox"/>	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>RL</i>	AW	M. HORIE, et al., Optical Data Storage, Proceedings of SPIE, vol. 4342, XP-002267102, pages 76-87, "MATERIAL CHARACTERIZATION AND APPLICATION OF EUTECTIC SbTe BASED PHASE-CHANGE OPTICAL RECORDING MEDIA", April, 2001					
<i>RL</i>	AX	Patent Abstracts of Japan, JP 10-241160, September 11, 1998					
<i>RL</i>	AY	Patent Abstracts of Japan, JP 61-020236, January 29, 1986					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner Mohammad Edun Primary Examiner						Date Considered <i>RL</i> 10/17/04	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



LIST OF RELATED CASES

<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Inventor/ Applicant</u>
238397US2 DIV*	10/657,121	09/09/03	NOBUKUNI et al.
250703US2 RE	10/825,439	04/16/04	NOBUKUNI et al.

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Muhammad Edun
Primary Examiner